


<b>Search Notes</b>  	<b>Application/Control No.</b>  09772986	<b>Applicant(s)/Patent Under Reexamination</b>  HAYASHI ET AL.
	<b>Examiner</b>  Tran, Thien F	<b>Art Unit</b>  2811

SEARCHED			
Class	Subclass	Date	Examiner
257	59,64-66,70,72,75,347	11/14/2007	TT

SEARCH NOTES		
Search Notes	Date	Examiner
search history printout	11/14/2007	TT
search history printout	11/15/2007	TT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner